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**CRYSTALLINITY DETERMINATION BY CURVEFIT PROCEDURE FOR A SEMI-
CRYSTALLINE POLYMER**

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SUMMARY

Wide angle x-ray scattering (WAXS) data from poly(etheretherketone) (PEEK) has been resolved into a crystalline contribution represented as 4 reflections and an amorphous contribution represented as a broad, smoothly varying curve, both contributions occurring in the 2θ range: 15-31 degrees. In this resolution the crystalline scatter is described as a linear combination of Cauchy and Gaussian functions while that of the amorphous halo is expressed as a cubic polynomial. Statistical analysis of the measured scattered intensity from an amorphous specimen with that calculated from the cubic polynomial, as a function of the combination parameter (fraction of Cauchy and Gaussian functions), suggests that the crystalline fraction of the polymer specimen studied is about 0.39. A listing of the FORTRAN IV program used in the resolution is provided in the Appendix.

INTRODUCTION

Composites fabricated from thermoplastic resins have some inherent differences in physical properties from those of the current thermoset resin composites and some formulations show considerable promise for structural applications. A partial listing of some of the potential advantages of such materials should include ease of formability, damage repair, and bonding as well as good environmental resistance and re-processing capability.¹⁻³ The concept of a thermoplastic implies the possibility of some degree of crystallization and with this possibility there is the promise of material property enhancement. Indeed, increased toughness, reduced moisture

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degradation, and the chemical resistance required for use in aerospace structures have been associated with crystallization in thermoplastic resin matrices.⁴

Poly(etheretherketone) (PEEK) is one of the thermoplastic matrix resins which can be fabricated as a semi-crystalline matrix in combination with a carbonaceous fiber reinforcement. This material has been characterized as having mechanical properties superior to those of currently used epoxies when tested under wet conditions at elevated temperatures.⁴ Physical property data and details of the synthesis of PEEK and other polyaryletherketones have been reported.^{5,6}

In order to understand the relationship between a desired physical property and an induced crystalline order in a matrix material a method for estimation of the degree of this order is necessary. Added complexity in a polymeric structure, e.g. changing from a one to a two phase material, is sure to have a far from straightforward effect on desired physical properties. It is well within reason to expect a small amount of added crystalline order to produce an increase in toughness, while a greater increase yields a brittle material. Hopefully a method for measuring crystalline order in a polymer matrix would also be useful in the presence of a carbonaceous reinforcement.

Wide angle x-ray scattering (WAXS) has been used to investigate the nature of the crystalline structure appropriate for the poly(arylether) and poly(aryletherketone) polymers.⁷⁻⁹ The basis for the interpretation of the WAXS data for PEEK and the other poly(aryletherketone) polymers has been the study of poly(p-phenylene oxide) (PPO) which is reported⁷ to crystallize in the space group Pbcn (space group No. 60, International Tables for X-ray

Crystallography). While PEEK is a more complicated polymer than PPO and requires at least six aryl units aligned along the c-axis of its unit cell for its description,^{6,8} the symmetry elements of Pbcn are appropriate for PEEK, as well as for PPO, and the major peaks in the WAXS data for this material can be indexed based upon the assumption of a structural analogy between the two materials.¹⁰ The four major crystalline reflections of PEEK, occurring at ~ 18.7 , 20.7 , 22.6 , and 28.7° (2θ), have, therefore, been indexed as 110, 113, 200, and 213, respectively, in strict analogy with the indexing of reference 9.

The purpose of this report is to describe an analytical procedure for the estimation of degree of crystalline order in a thermoplastic polymer matrix. Semicrystalline PEEK, a material of possible future use in aerospace applications, has been used to develop and illustrate this procedure. Intensity versus diffraction angle data taken from a flat powder specimen in a WAXS experiment has been used for the analysis. In order to build in a certain realism and thus to facilitate extension to real specimens of composites reflection geometry has been used to obtain the data. While the computer program developed for the analysis and presented in the Appendix is specialized for PEEK it is readily convertible to other formulations for which the major x-ray diffraction reflections are known.

ANALYTICAL

Various methods for the determination of degree of crystalline order in polymeric materials using WAXS data have been employed, some of which have achieved an almost standard practice status. A sampling of these methods,

in order of increasing ease of application, vary from a difficult to use but sophisticated absolute method,¹¹ through a more practical though less rigorous absolute procedure,¹² through a well-regarded index procedure,^{13,14} to a surprisingly useful 2-point index method.¹⁵ All of these would be confounded by the presence of the carbonaceous reinforcement and involve factors such as a requirement for multiple samples, transmission geometry, interpolation between standards, and for some, even an element of subjectivity. For those polymers with known crystal structure, however, a crystallinity determination by curvefit procedure¹⁶ is feasible and in theory, at least, is unaffected by the previously mentioned factors and may even be practicable in the presence of the carbonaceous reinforcement.

The basis of the curvefit procedure¹⁶ is the expression of the measured x-ray intensity data versus diffractometer angle (2θ) for the polymeric specimen as a sum of the x-ray scatter from the known crystalline peaks plus that characteristic of the broad, smoothly varying paracrystalline or amorphous scatter. The crystalline peaks are described as a linear combination of Cauchy and Gaussian expressions with the linear combination parameter varying from 0 for a pure Cauchy function to 1 for a pure Gaussian function with intermediate values representing a combination of the 2 functions. The amorphous background scatter is expressed as a cubic polynomial.

Each crystalline peak is defined by parameters representing the peak height, peak position, and width of the peak at half maximum, while the cubic polynomial is defined by 4 parameters. Thus, the expression for the summation of the crystalline peaks plus that of the background curve for the 4 reflections representative of PEEK in the 2θ range of interest contains 16

independent variables to be determined by the curvefit procedure. These independent variables were determined by solving the system of nonlinear equations, i.e. the summation of the expressions for the crystalline reflections and background curve as a function of the diffraction angle minus the measured intensity value at that angle, by using Levenberg-Marquardt and Gauss algorithms for the nonlinear least squares approximations.¹⁷ The computer program, which solves for these variables and which contains the Langley computing center's library routine, MARQ,¹⁸ is presented in the Appendix for a real case. Convergence of the modified Marquardt algorithm is satisfied when the difference of the residual sum of squares estimates on two successive iterations divided by the residual at the first of these iterations is equal to or less than an input parameter based upon the relative accuracy of the equations.¹⁸

Once the parameters have been obtained, an integration or comparable mathematical procedure may be used to extract the relative areas under the various curves. An obvious first approximation to the polymeric crystalline fraction would then be the summation of the areas under the crystalline reflections divided by the area under all curves. There is apparently some controversy about this, however, since some workers¹² report different constants of proportionality for relating the crystalline and amorphous fractions to the respective integral intensities (areas). Other workers,¹⁹ base their data reduction upon the "Law of Conservation of Intensity",²⁰ in effect, choosing the more simple procedure. Since the present goal is the description of an analytical procedure as applied to a specific thermoplastic material and since only one crystalline specimen was required

to develop and illustrate this procedure, the more simple expression for crystalline fraction is presented.

EXPERIMENTAL

WAXS data has been obtained on annealed and melt-quenched PEEK material. $\text{CuK}\alpha$ radiation was used with an automated powder x-ray diffractometer equipped with a curved crystal, graphite monochromator. With the generator operated at 45 kV and 40 mA, the intensity of 1 s counts taken every 0.01 degrees (2θ) was recorded on hard disk. The data in the angular range $15.00\text{--}30.83^\circ$, an adequate range for evaluation of crystalline fraction,¹² was used for the present analysis.

Commercially synthesized polymeric material, received in the form of compression mouldings, was melted in a hot press and immediately quenched in ice water to produce a light brown, transparent film which had a density of 1.267 g cm^{-3} as determined by immersion in a toluene-carbon tetrachloride density gradient column. This film was cooled to dry ice temperature, ground in a rotary mill, and sieved using a 60 mesh screen. Part of the material which passed through the screen was used as is (the melt-quenched specimen) and part was annealed in a vacuum oven at 267°C for 72 h to induce crystallinity. The density of this annealed material (the crystalline specimen) was determined to be 1.295 g cm^{-3} .

RESULTS AND DISCUSSION

The mathematical expression used to describe the crystalline reflections contains a linear combination parameter which controls their

geometrical shape. When this combination parameter has the value 0, the reflections are characterized as pure Cauchy functions, and when its value is 1 they are represented as pure Gaussians. Intermediate values of the parameter produce composite representations of the reflections. Figure 1 presents a series of 10 plots (Figures 1(a) - 1(k)) depicting the changes incurred in the crystalline peaks and the background curve as the linear combination parameter is varied from 1.0 to 0.0 in 0.1 increments. They are compared on each plot with the actual measured data of semi-crystalline PEEK appearing at the top of the figure as a curve composed of a series of points over the angular range $15.00\text{--}30.83^\circ$ (2θ). The indices describing the crystalline reflections are included in Figure 1(a).

As the description of the crystalline peaks changes from pure Gaussian (Fig. 1(a)) to pure Cauchy (Fig. 1(k)) tailing at the base of the peaks increases uniformly. This increased tailing produces a directly related increase in the area of the crystalline peaks, which increase at the expense of the background area. The fractional crystalline area, which is the sum of areas under the 4 crystalline peaks divided by this sum plus the area under the background curve, varies with the increased tailing from 0.2502 to 0.3916 in arbitrary intensity-degree units. This fractional crystalline area is related to a degree of crystalline order with the assumption of equivalent scatter from equivalent phases. In all cases there is insignificant difference between the calculated area under the measured curve and the calculated summation of all curvefit areas.

Since the summation of crystalline areas plus the area under the background curve is essentially constant, and since the summation of the crystalline areas changes with the linear combination parameter, the shape

of the background curve (as well as its area) also changes with this parameter. A comparison of this background curve with that measured for amorphous PEEK, normalized for equal area, is presented in Figure 2, as a function of the linear combination parameter. There is a progressive observable difference in the relationship between the 2 compared curves presented in Figures 2(a) and 2(b); however, a statistical analysis was performed to minimize the necessity for subjective judgment as to the quality of a representation. The simple correlation coefficients between the set of points describing the background curve as a function of the linear combination parameter and the measured data for an amorphous specimen, each having 1584 observations, were determined and are presented in Table I.

The variation of the amorphous area, fractional crystalline area, and correlation coefficient as the form of the crystalline peak shape is systematically varied from that of a pure Cauchy function to that of a pure Gaussian function is presented in Table I. There is displayed a systematic increasing trend in the correlation coefficient with increasing Cauchy character suggesting that for the present WAXS experiment with semi-crystalline PEEK powder the pure Cauchy description of the crystalline peak shape is preferred. Others, however, have reported a linear combination parameter of 0.5 to yield the best fit for many synthetic and natural fibers,¹⁶ while another worker analyzed nylon data using pure Cauchy expressions.²¹ Concomitant with the present trend is the determination that the crystalline fraction of the annealed PEEK is 0.39.

CONCLUDING REMARKS

A curvefit procedure, based upon the modified Marquardt algorithm, has been developed and illustrated with semi-crystalline PEEK. Intensity versus diffraction angle data taken from flat powder specimens (crystalline and amorphous) in reflection geometry has been used for the analysis. While the method was designed to be based upon one semi-crystalline sample only, an amorphous specimen was required to discriminate between the various solutions. Extention of the analytical procedure (and computer program) to other systems, such as PEEK composites containing carbonaceous fiber, should be straightforward.

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Table I. Results of Curvefitting Procedure and Statistical Analysis as a Function of the Linear Combination Parameter for Semi-crystalline PEEK Polymer Matrix.

COMBINATION PARAMETER*	AMORPHOUS AREA**	FRACTIONAL CRYSTALLINE AREA	CORRELATION COEFFICIENT***
0.0	23441	.3916	.9705
0.1	24079	.3751	.9701
0.2	24690	.3592	.9698
0.3	25276	.3440	.9694
0.4	25842	.3293	.9692
0.5	26388	.3151	.9690
0.6	26917	.3014	.9687
0.7	27431	.2881	.9685
0.8	27930	.2751	.9683
0.9	28416	.2625	.9681
1.0	28891	.2502	.9679

*A linear combination parameter of 0.0 implies a pure Cauchy function while that of 1.0 implies a pure Gaussian expression.

**Area under amorphous halo in intensity - degree units relative to an area under the measured intensity envelope of 38530.

***A measure of how well the shape of the derived cubic polynomial, describing the amorphous halo, is correlated to the measured shape of an amorphous PEEK specimen.

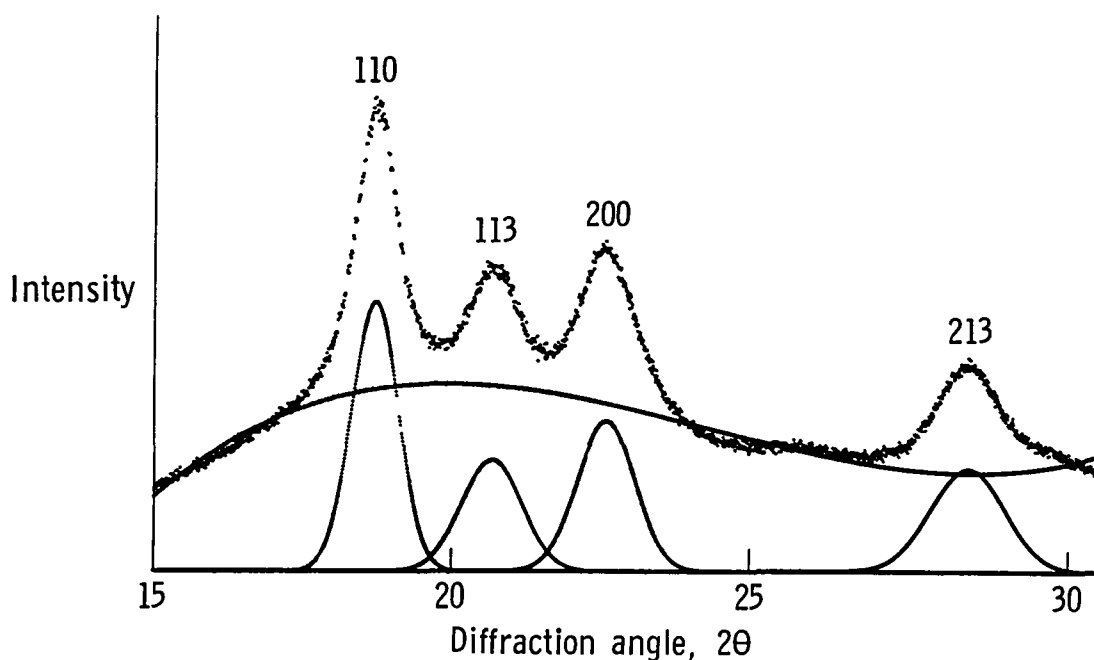


Figure 1(a). - X-ray diffractogram of semi-crystalline PEEK compared to resolved crystalline scatter represented as a linear combination of Cauchy and Gaussian functions and the amorphous halo represented by a cubic polynomial. Combination parameter = 1.0. Fractional crystalline area = 0.2502.

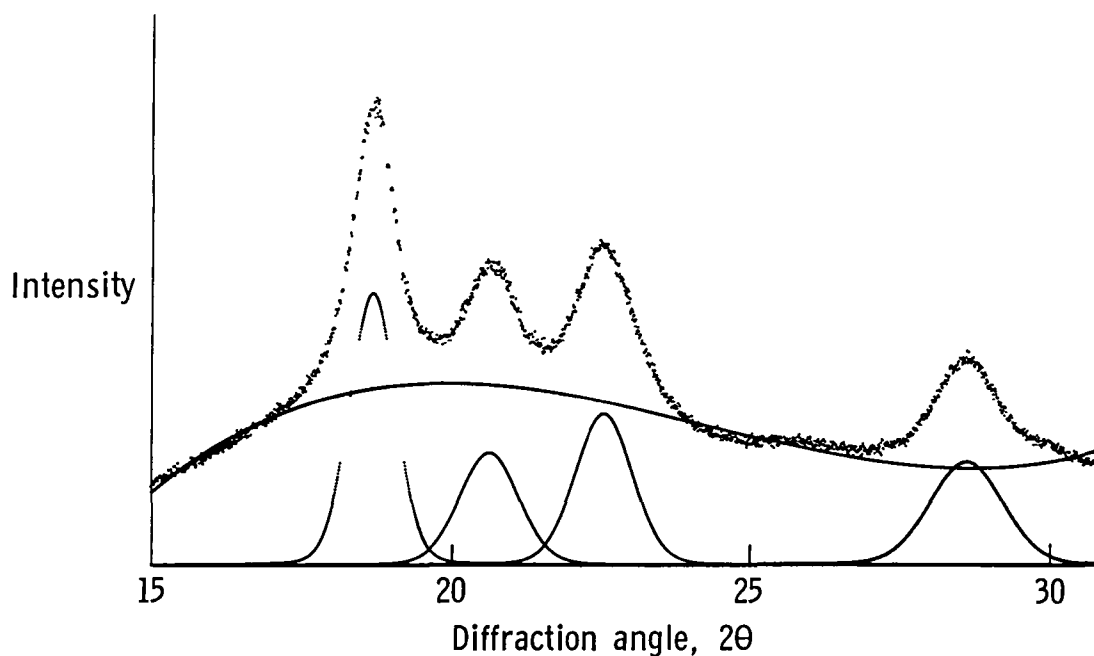


Figure 1(b). - Combination parameter = 0.9. Fractional crystalline area = 0.2625.

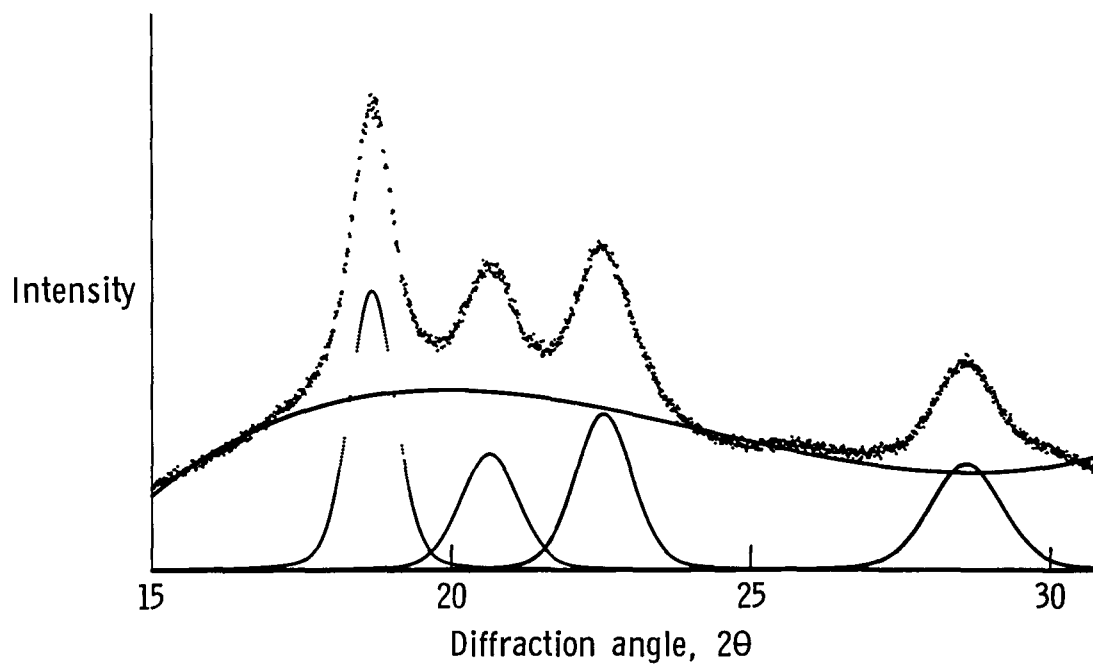


Figure 1(c). - Combination parameter = 0.8. Fractional crystalline area = 0.2751.

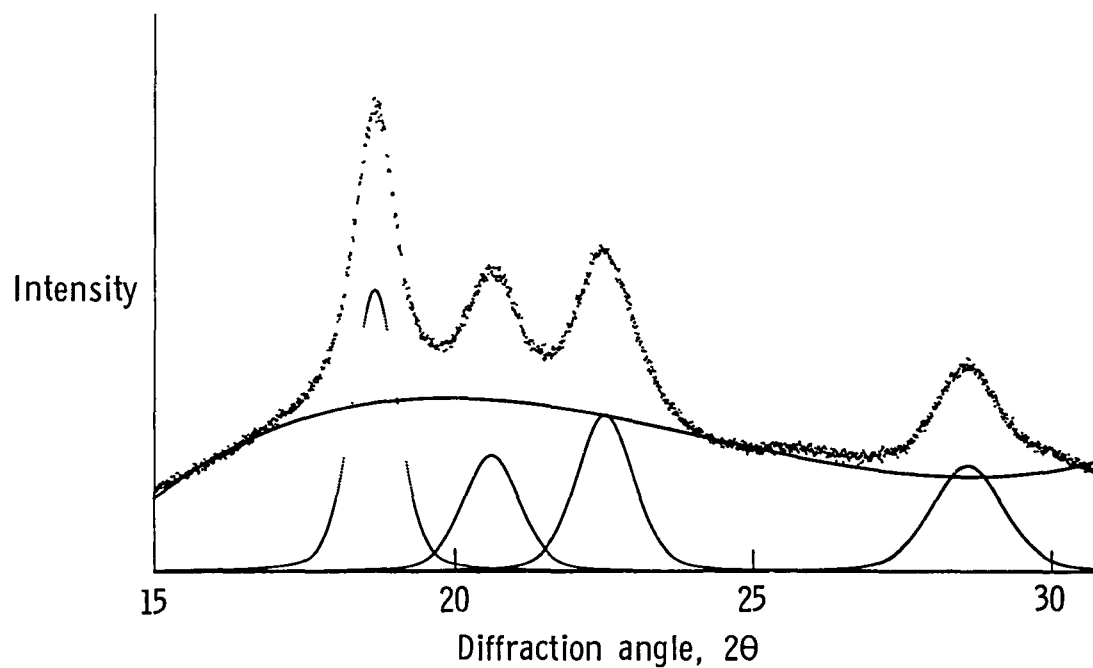


Figure 1(d). - Combination parameter = 0.7. Fractional crystalline area = 0.2881.

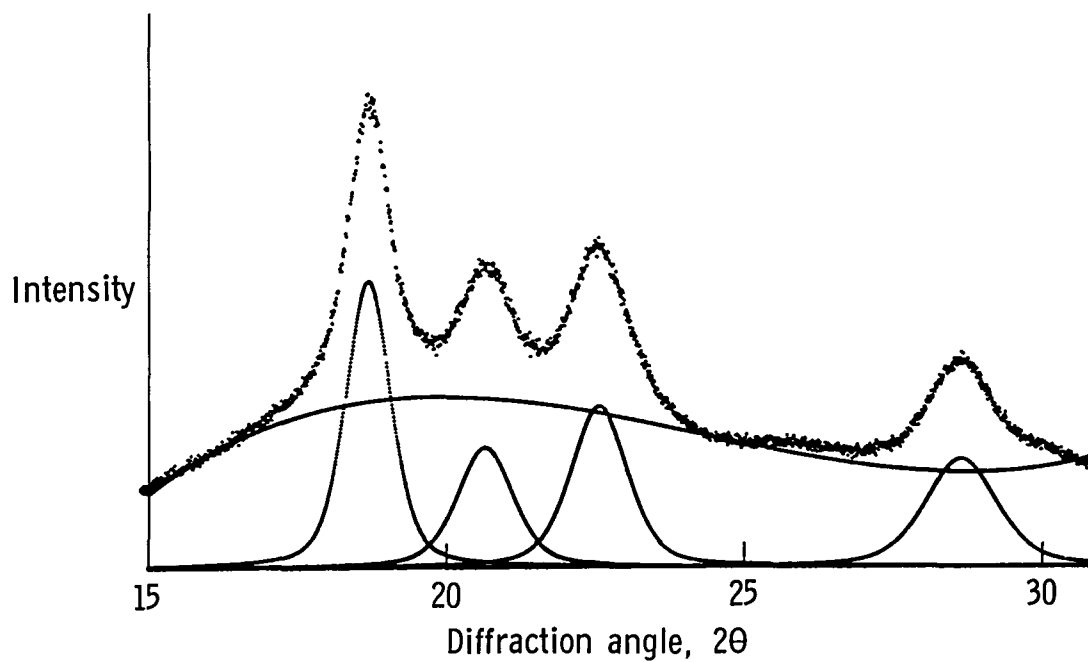


Figure 1(e). - Combination parameter = 0.6. Fractional crystalline area = 0.3014.

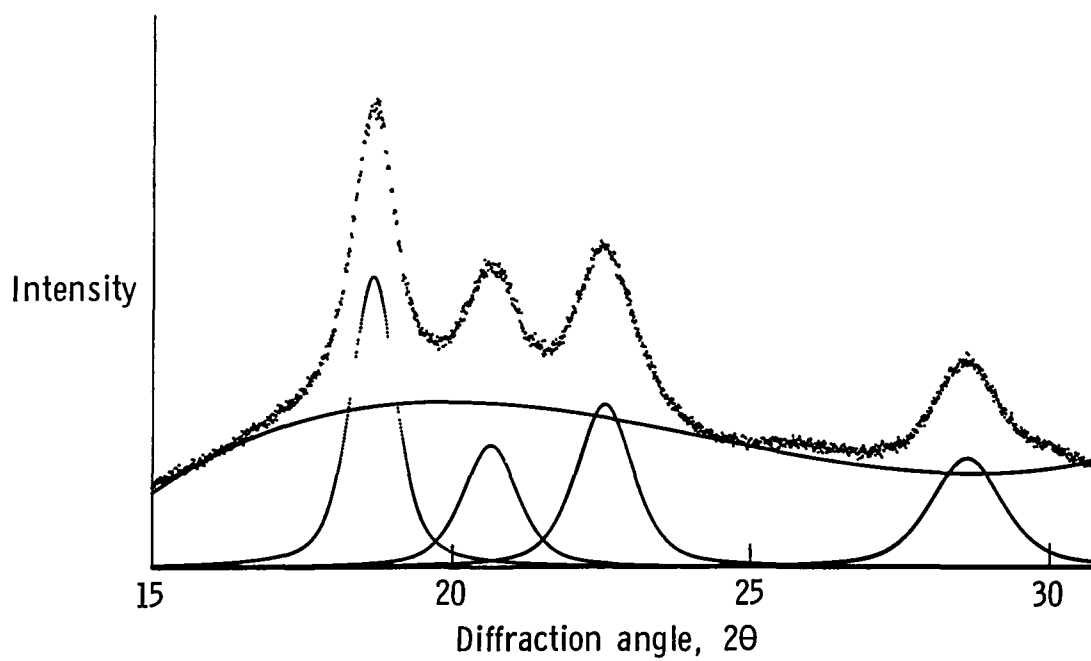


Figure 1(f). - Combination parameter = 0.5. Fractional crystalline area = 0.3151.

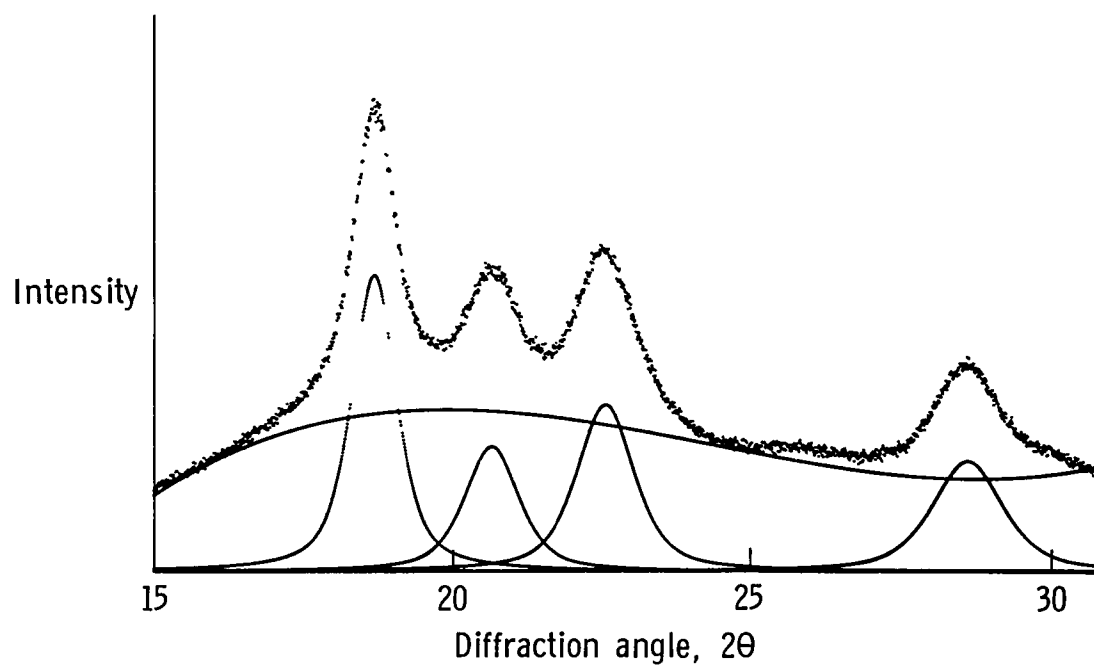


Figure 1(g). - Combination parameter = 0.4. Fractional crystalline area = 0.3283.

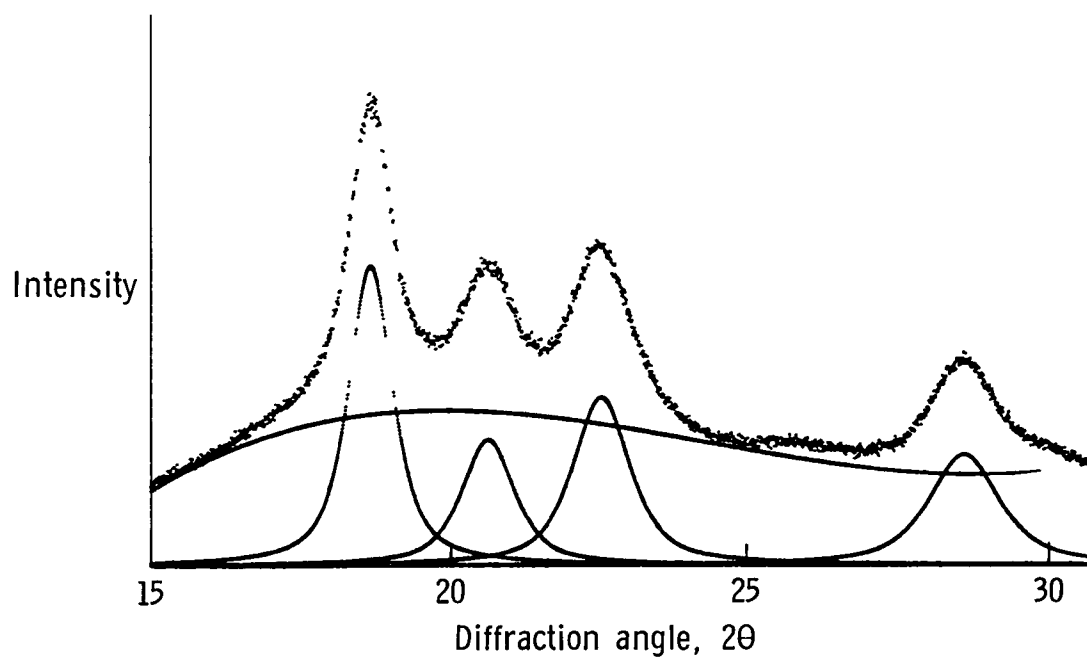


Figure 1(h). - Combination parameter = 0.3. Fractional crystalline area = 0.3440.

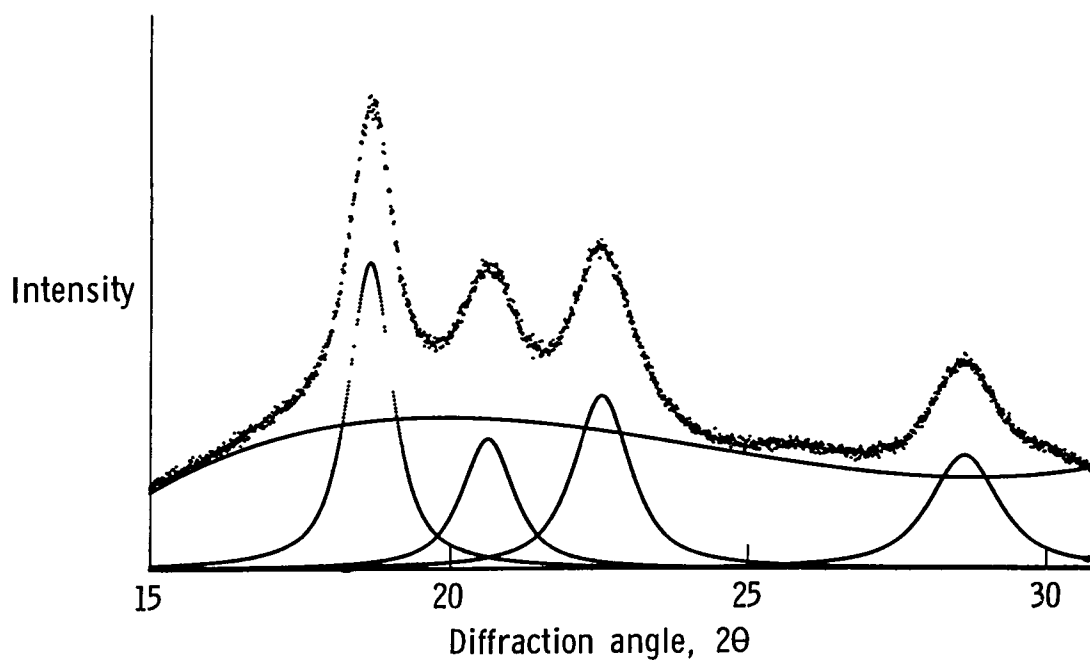


Figure 1(i). - Combination parameter = 0.2. Fractional crystalline area = 0.3592.

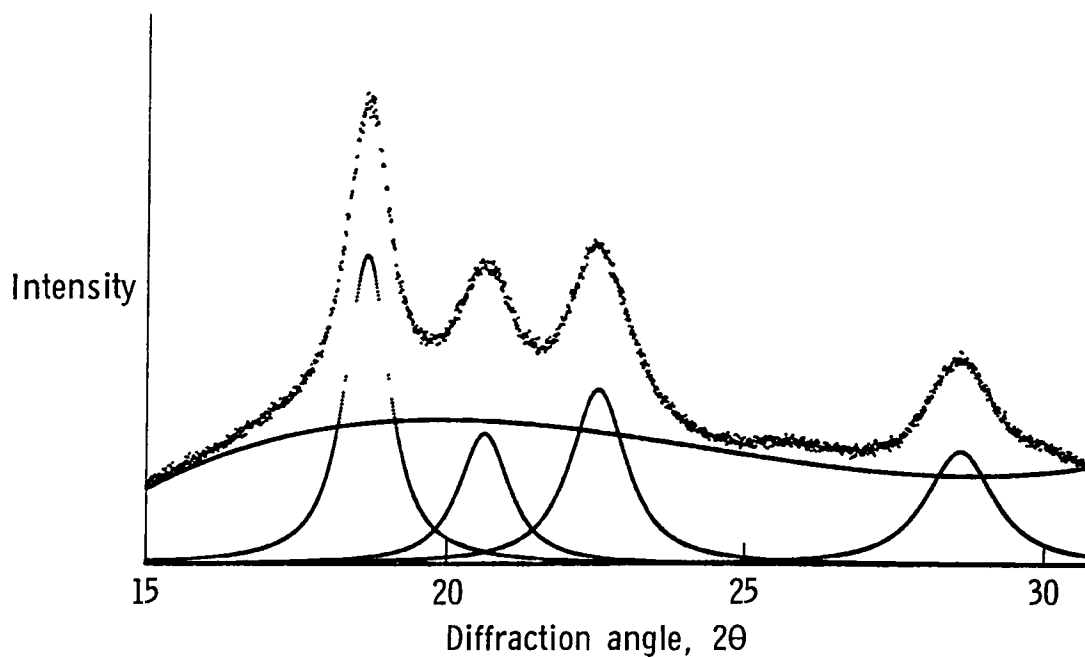


Figure 1(j). - Combination parameter = 0.1. Fractional crystalline area = 0.3751.

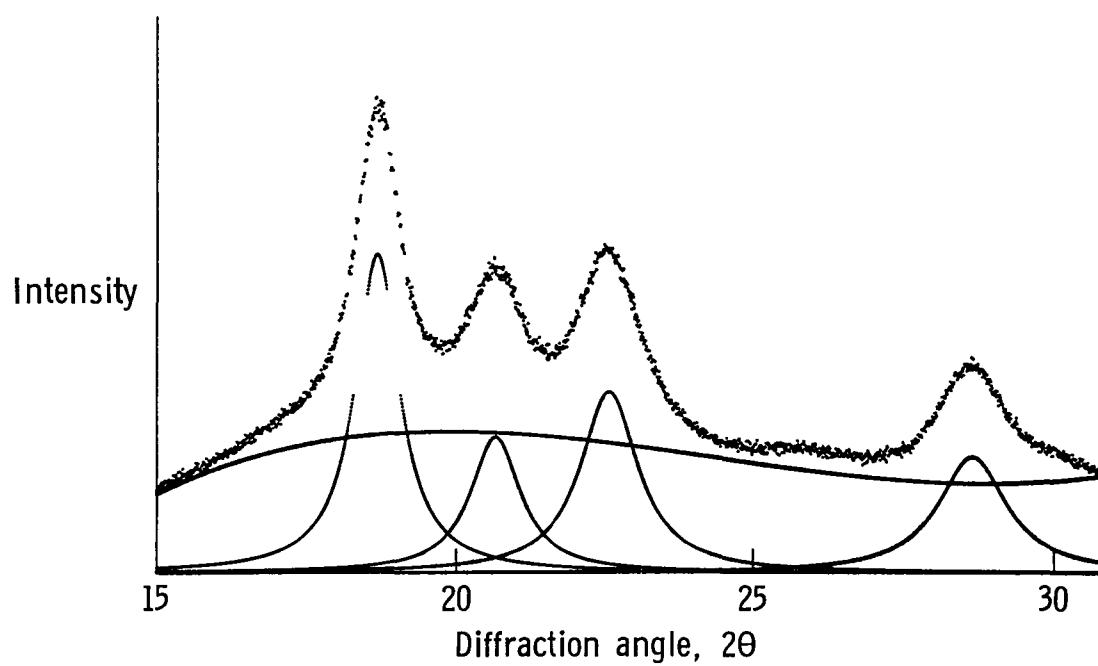


Figure 1(k). - Combination parameter = 0.0. Fractional crystalline area = 0.3916.

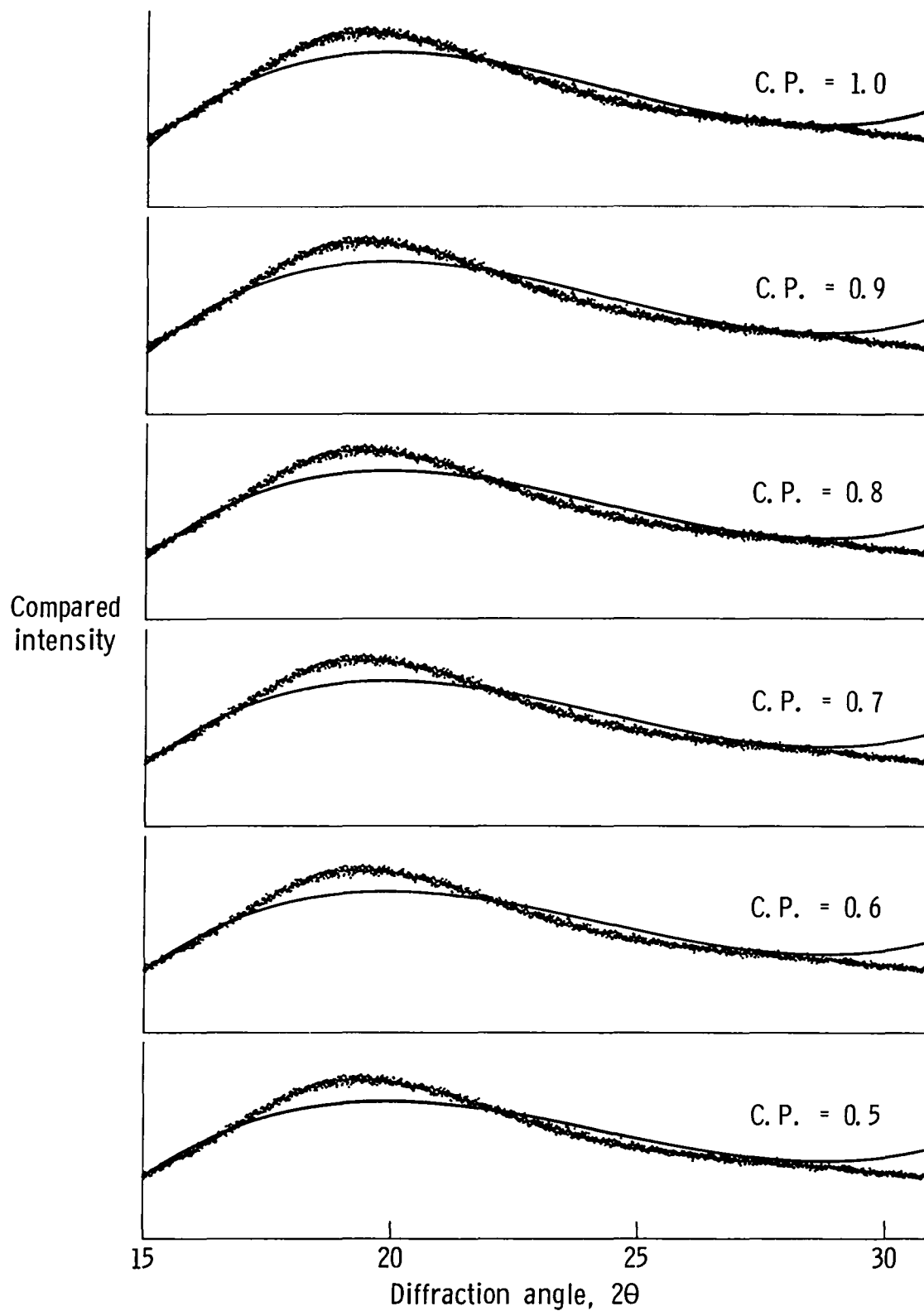


Figure 2(a). - Amorphous halo as represented by a cubic polynomial compared with data from amorphous PEEK, normalized for equal area, for combination parameters varying from 0.5 to 1.0.

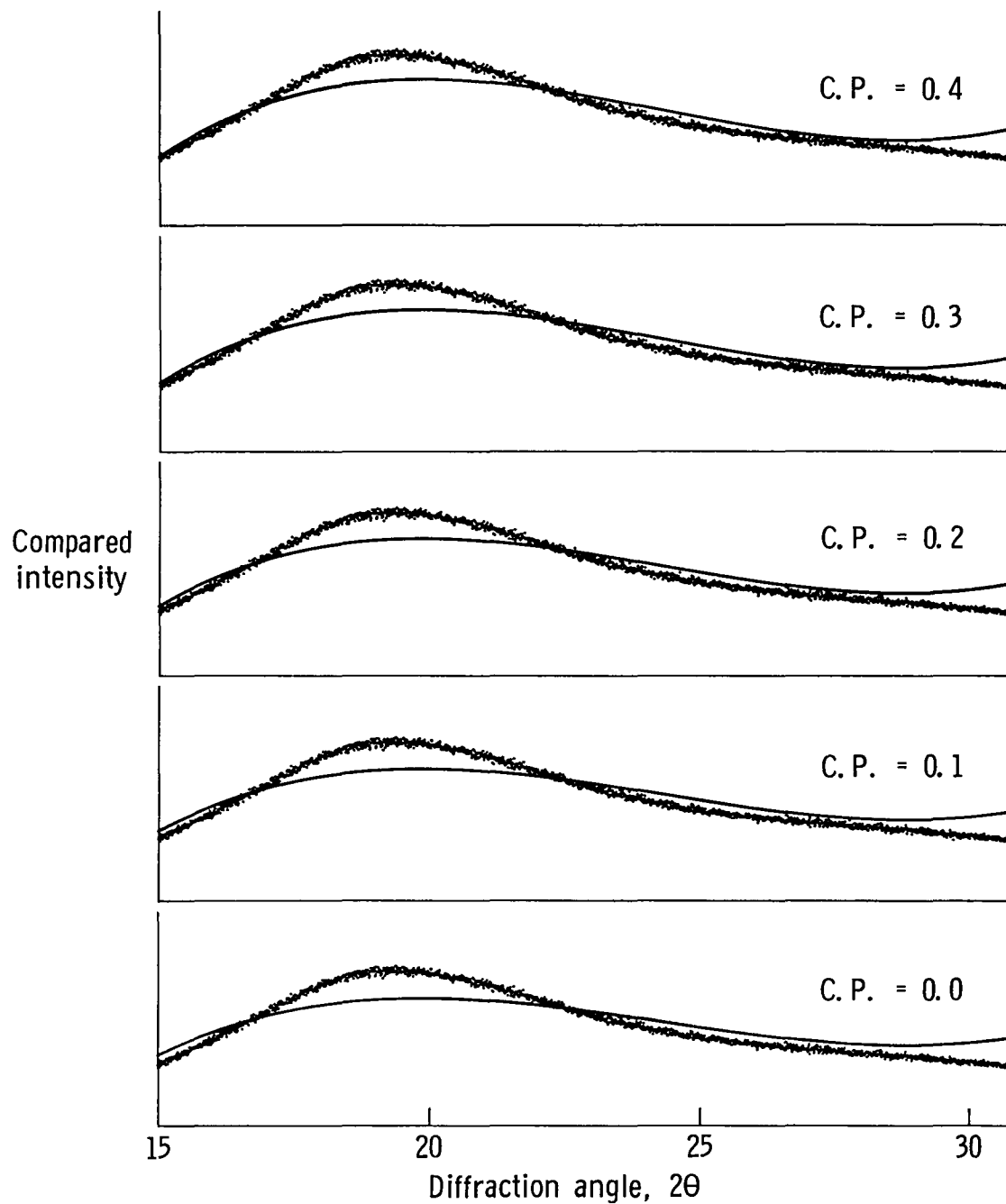


Figure 2(b). - Amorphous halo as represented by a cubic polynomial compared with data from amorphous PEEK, normalized for equal area, for combination parameters varying from 0.0 to 0.4.

APPENDIX I. A FORTRAN IV COMPUTER PROGRAM FOR THE RESOLUTION OF POLYMER MATRIX CRYSTALLINE SCATTER

The code listed in this Appendix represents that used to calculate one of the cases presented in this report. A dummy call to a PLOT routine is used since these routines are, in general, arbitrary and thus not transportable. Subroutine MARQ, which solves a system of N nonlinear equations in N unknowns for the real roots by the modified Marquardt algorithm, is a Langley Research Center library routine. (Mathematical and Statistical Software at Langley, Central Scientific Computing Complex Document N-3, April 1984).

```

PROGRAM MARFIT(INPUT,OUTPUT,TAPE5=INPUT,TAPE6=OUTPUT)
EXTERNAL F
COMMON TT, XRI, G
  DIMENSION X(16), FX(1584), WK(33800), TT(1584), XRI(1584)
  DIMENSION IRAY(6)
  DIMENSION IN(24)
  DATA IRAY/6 * (-0)/
  DATA M/1584/, N/16/, C/1.0/, EPS/1.0E-08/, NSIG/5/, ITMAX/100/
  DATA X/ 2766.,          18.71,          1.0,
1      952.,          20.67,          1.0,
2      1570.,          22.56,          1.0,
3      1008.,          28.65,          1.0,
5      -9500.,          1300.,          -50.,
6      0.600/
COMMENT.  INITIALIZE G AT THIS TIME
  G = 0.5
COMMENT: OBTAIN X-RAY INTENSITIES FROM ARBITRARY FILE
  DO 5 I=1,M
  READ(5,3) IN
3  FORMAT(8(A1,A5,A4))
C  IF(IN(2) .EQ. 5H10.00) GO TO 6
  IF(IN(2) .EQ. 5H14.98) GO TO 6
5  CONTINUE
6  PRINT4,IN(2)
4  FORMAT(1X,A5)
  I1 = 1
  I2 = I1 + 7
  DO 25 I3 = 1,6
  DO 50 I4 = 1,31
  READ(5,7) (XRI(I),I=I1,I2)
7  FORMAT(10X,8(F7.0))
  I1 = I1 + 8
  I2 = I2 + 8
50 CONTINUE
  I2 = I2 - 6
  READ(5,8) (XRI(I),I=I1,I2)
8  FORMAT(10X,2(F7.0))
  I1 = I1 + 2
  I2 = I1 + 7
25 CONTINUE
  DO 26 J=1501,1584,8
  KEND=J+7
  IF(J .EQ. 1581)KEND=1584
  READ(5,7) (XRI(I),I=J,KEND)
26 CONTINUE
  PRINT*,KEND
COMMENT: WE NOW HAVE 1584 XRI'S
  IRAY(4) = 0
  CALL SYSTEMC (115,IRAY)
  PRINT1
1  FORMAT(1H1,18X,17HEXPERIMENTAL DATA)
  PRINT2
2  FORMAT(1H0,13X,9H 2-THETA ,10X,9HINTENSITY,/)
COMMENT: GENERATE 2-THETA'S CORRESPONDING TO XRI'S

```

```

      T = 14.99
      DO 100 I=1,M
      T = T + 0.01
      TT(I) = T
100 CONTINUE
105 CONTINUE
COMMENT: MARQ USES GAUSS AND LEVENBERG-MARQUARDT ALGORITHMS
C   TO RESOLVE WAXS INTO CRYSTALLINE AND PARACRYSTALLINE CONTRIBUTIONS
      CALL MARQ(M,N,X,C,EPS,NSIG,ITMAX,FX,F,WK,IERR)
      PRINT150,G
150 FORMAT(1H0,3HG =,G22.14)
      PRINT900,IERR
      IF(IERR .NE. 0) GO TO 10
C   WRITE(6,901) (X(I),I=1,N), (FX(I),I=1,M), ITMAX
      PRINT200
200 FORMAT(1H1,25X,15HSOLUTION VECTOR,/)
      PRINT250
250 FORMAT(1H0,5X,11HPEAK HEIGHT,10X,13HPEAK POSITION,7X,17HWIDTH AT 1
1/2 MAX.,/)
      NX = N - 4
      PRINT300, (X(I),I=1,NX)
300 FORMAT (1H ,3G22.14)
      PRINT325
325 FORMAT(1H0,35X,23HPOLYNOMIAL COEFFICIENTS)
      NP = NX+1
      PRINT350, (X(I), I=NP,N)
350 FORMAT(1H0,4G22.14)
      PRINT400
400 FORMAT(1H1,30X,19HVALUES OF EQUATIONS,////)
      PRINT300, (FX(I),I=1,M)
      PRINT500,ITMAX
500 FORMAT(23HONUMBER OF ITERATIONS =,I4)
      CALL AREA(X,M,N)
      CALL PLOT(X,M,N)
      GO TO 20
10 WRITE(6,902) (X(I),I=1,N)
      PRINT500,ITMAX
20 STOP
900 FORMAT(13HOERROR CODE =,I4)
901 FORMAT(18HOSOLUTION VECTOR =,3G22.14/22HVALUES OF EQUATIONS =,
1      4G22.14/23HONUMBER OF ITERATIONS =,I3)
902 FORMAT(33HOLAST APPROXIMATION TO SOLUTION =,3G22.14)
      END
      SUBROUTINE PLOT(X,M,N)
      RETURN
      END
      SUBROUTINE F(X,M,N,FX)
      COMMON TT, XRI, G
      DIMENSION X(N), FX(M), TT(1584), XRI(1584)
      DIMENSION PH(4), PP(4), PW(4), EQ(4)
      A1 = X(N-3)
      A2 = X(N-2)
      A3 = X(N-1)
      A4 = X(N)

```

```

DO 100 I=1,M
INDEX = 0
DO 200 L=1,4
PH(L) = X(L+INDEX)
PP(L) = X(L+1+INDEX)
PW(L) = X(L+2+INDEX)
INDEX = INDEX + 2
EQ(L) = (G *PH(L) * EXP(-ALOG(2.0)*((2.0*(TT(I)- PP(L)) / PW(
1 L))**2.0)))+ (((1.0-G)*PH(L))/ (1.0+(((2.0*(TT(I)- PP(L)) / PW(
2 L))**2.0)))
200 CONTINUE
B = A1 + (A2*TT(I)) + (A3*(TT(I)**2)) + (A4*(TT(I)**3))
50 CONTINUE
FX(I) = EQ(1) + EQ(2) + EQ(3) + EQ(4) - XRI(I) + B
100 CONTINUE
RETURN
END
SUBROUTINE AREA(X,M,N)
COMMON TT, XRI, G
DIMENSION TT(1584), XRI(1584), CP(1584)
DIMENSION PH(4), PP(4), PW(4), EQ(1584,4)
DIMENSION IRAY(6)
DIMENSION B(4), X(16)
DATA IRAY/6 * (-0)/
IRAY(4) = 0
CALL SYSTEMC (115,IRAY)
DO 110 I=1,M,8
PRINT6,XRI(I),XRI(I+1), XRI(I+2),XRI(I+3),XRI(I+4),XRI(I+5),XRI(I+
26),XRI(I+7)
6 FORMAT(1H ,10X,8F10.2)
110 CONTINUE
DO 111 I=1,M,8
PRINT6,TT(I),TT(I+1),TT(I+2),TT(I+3),TT(I+4),TT(I+5),TT(I+6),TT(I+
27)
111 CONTINUE

B1 = X(N-3)
B2 = X(N-2)
B3 = X(N-1)
B4 = X(N)
DO 150 I=1,M
INDEX = 0
DO 200 L=1,4
PH(L) = X(L+INDEX)
PP(L) = X(L+1+INDEX)
PW(L) = X(L+2+INDEX)
INDEX = INDEX + 2
EQ(I,L) = (G *PH(L) * EXP(-ALOG(2.0)*((2.0*(TT(I)- PP(L)) / PW(
1 L))**2.0)))+ (((1.0-G)*PH(L))/ (1.0+(((2.0*(TT(I)- PP(L)) / PW(
2 L))**2.0)))
200 CONTINUE
CP(I) = B1 + B2 *TT(I) + B3 *(TT(I)**2) + B4 *(TT(I)**3)
150 CONTINUE

```


COMMENT XRI=X-RAY INTENSITY; TAE=TOTAL AREA UNDER ENVELOPE

```
TAE = 0.0
A1 = 0.0
A2 = 0.0
A3 = 0.0
A4 = 0.0
A5 = 0.0
PC = 0.0
DO 225 I=1,M
TAE = TAE + XRI(I)
A1 = A1 + EQ(I,1)
A2 = A2 + EQ(I,2)
A3 = A3 + EQ(I,3)
A4 = A4 + EQ(I,4)
PC = PC + CP(I)
```

225 CONTINUE

COMMENT: GENERATE AREAS

```
BASE = TT(M) - TT(1)
TAE = (TAE/M) * BASE
A1 = (A1/M) * BASE
A2 = (A2/M) * BASE
A3 = (A3/M) * BASE
A4 = (A4/M) * BASE
PC = (PC/M) * BASE
TOTAL = A1 + A2 + A3 + A4 + PC
XTAL = (A1 + A2 + A3 + A4) / TOTAL
```

PRINT10,TAE,TOTAL

10 FORMAT(1H ,//,1X,47HTOTAL AREA UNDER MEASURED INTENSITY ENVELOPE =

1 ,F14.4,10X,15H(TOTAL PEAKS = ,F14.4,1H))

PRINT11,A1,A2,A3,A4,A5

11 FORMAT(1H0,28HAREAS OF DIFFRACTION PEAKS: ,5(F14.4,3X))

PRINT12,PC

12 FORMAT(1H0,34HAREA OF PARACRYSTALLINE SCATTER = ,F14.4)

PRINT13,XTAL

13 FORMAT(1H0,23HCRYSTALLINE FRACTION = ,F14.4)

RETURN

END

SUBROUTINE MARQ(M,N,X,C,EPS,NSIG,ITMAX,FX,F,WK,IERR)

MARQ 2

C

DIMENSION WK(5),X(1),FX(1)

MARQ 90

EXTERNAL F

MARQ 91

INDWK1 = 5*N+2*M+(N+1)*N/2+1

MARQ 92

INDWK2 = INDWK1+1

MARQ 96

INDWK3 = INDWK2+M*N

MARQ 97

IOPT = 0

MARQ 98

DELTA = 0.0

MARQ 99

MAXFN = (ITMAX+1) * (N+1)

MARQ 100

CALL QXZ031(F,M,N,NSIG,EPS,DELTA,MAXFN,IOPT,C,X,WK(INDWK1),FX,

MARQ 101

*WK(INDWK2),M,WK(INDWK3),WK,INFER,IERR)

QXZNA270

ITMAX = WK(5)

MARQ 103

RETURN

MARQ 104

END

MARQ 105

SUBROUTINE QXZ031(F,M,N,NSIG,EPS,DELTA,MAXFN,IOPT,PARM,X,SSQ,

MARQ 106

QXZNA273

	*	FX,XJAC,IXJAC,XJTJ,WK,INFER,IERR)	ZXSSQL 3
C		THE SOLUTION X IS A STATIONARY POINT.	ZXSSQ150
C			ZXSSQ170
	DIMENSION	X(N),FX(M),PARM(5),XJAC(1),XJTJ(1),WK(6)	ZXSSQ171
C		XJAC USED INTERNALLY IN PACKED FORM	ZXSSQ172
	REAL	AL,CONS2,DELTA,DNORM,DSQ,EPS,	ZXSSQ173
	*	ERL2,ERL2X,FX,FO,FOSQ,FOSQS4,G,HALF,	ZXSSQ174
	*	XJTJ,HH,ONE,ONEP10,ONEP5,ONESFO,AX,	ZXSSQ175
	*	PREC,REL,RHH,SIG,SQDIF,SSQ,SSQOLD,SUM,TEN,	ZXSSQ176
	*	TENTH,X,XDIF,XHOLD,XJAC,UP,WK,ZERO,	ZXSSQ177
	*	XDABS,RELCON,PARM,PO1,TWO,HUNTW,DELTA2	ZXSSQ178
	EXTERNAL F		ZXSSQ179
	DATA	SIG/14.4/	ZXSSQ180
	DATA	AX/0.1/	ZXSSQ181
	DATA	PO1,TENTH,HALF,ZERO,ONE,ONEP5,TWO,	ZXSSQ182
	*	TEN,HUNTW,ONEP10/0.01,0.1,0.5,0.0,	ZXSSQ183
	*	1.,1.5,2.,10.0,1.2E2,1.E10/	ZXSSQ184
C		ERROR CHECKS	ZXSSQ185
	IERR = 0		ZXSSQ186
	IF (M.LE.0.OR.M.GT.IXJAC.OR.N.LE.0.OR.IOPT.LT.0.OR.IOPT.GT.2		ZXSSQ187
C	.OR. PARM(1) .LE. 0.0) GO TO 305		ZXSSQ188
	IMJC = IXJAC-M		ZXSSQ189
	IF (IOPT.NE.2) GO TO 5		ZXSSQ190
	IF (PARM(2).LE.ONE.OR.PARM(1).LE.ZERO) GO TO 305		ZXSSQ191
C		MACHINE DEPENDENT CONSTANTS	ZXSSQ192
5	PREC = TEN**(-SIG-ONE)		ZXSSQ193
	REL = TEN**(-SIG*HALF)		ZXSSQ194
	RELCON = TEN**(-NSIG)		ZXSSQ195
C		WORK VECTOR IS CONCATENATION OF	ZXSSQ196
C		SCALED HESSIAN,GRADIENT,DELX,SCALE,	ZXSSQ197
C		XNEW,XBAD,F(X+DEL),F(X-DEL)	ZXSSQ198
	IGRAD1 = ((N+1)*N)/2		ZXSSQ199
	IGRADL = IGRAD1+1		ZXSSQ200
	IGRADU = IGRAD1+N		ZXSSQ201
	IDELX1 = IGRADU		ZXSSQ202
	IDELXL = IDELX1+1		ZXSSQ203
	IDELXU = IDELX1+N		ZXSSQ204
	ISCAL1 = IDELXU		ZXSSQ205
	ISCALL = ISCAL1+1		ZXSSQ206
	ISCALU = ISCAL1+N		ZXSSQ207
	IXNEW1 = ISCALU		ZXSSQ208
	IXNEWL = IXNEW1+1		ZXSSQ209
	IXBAD1 = IXNEW1+N		ZXSSQ210
	IFPL1 = IXBAD1+N		ZXSSQ211
	IFPL = IFPL1+1		ZXSSQ212
	IFPU = IFPL1+M		ZXSSQ213
	IFML1 = IFPU		ZXSSQ214
	IFML = IFML1+1		ZXSSQ215
	IMJC = IXJAC - M		ZXSSQ216
C		INITIALIZE VARIABLES	ZXSSQ217
	AL = PARM(1)		ZXSSQ218
	CONS2 = 0.0		ZXSSQ219
	IF (IOPT.EQ.0) GO TO 20		ZXSSQ220
	IF (IOPT.EQ.1) GO TO 10		ZXSSQ221

	AL = PARM(1)	ZXSSQ222
	FO = PARM(2)	ZXSSQ223
	UP = PARM(3)	ZXSSQ224
	CONS2 = PARM(4)*HALF	ZXSSQ225
	GO TO 15	ZXSSQ226
10	AL = P01	ZXSSQ227
	FO = TWO	ZXSSQ228
	UP = HUNTW	ZXSSQ229
	CONS2 = TENTH	ZXSSQ230
15	ONESFO = ONE/FO	ZXSSQ231
	FOSQ = FO*FO	ZXSSQ232
	FOSQS4 = FOSQ**4	ZXSSQ233
20	IEVAL = 0	ZXSSQ234
	DELTA2 = DELTA*HALF	ZXSSQ235
	ERL2 = ONEP10	ZXSSQ236
	IBAD = -99	ZXSSQ237
	ISW = 1	ZXSSQ238
	ITER = -1	ZXSSQ239
	INFER = 0	ZXSSQ240
	IERR = 0	ZXSSQ241
	DO 25 J=IDELXL, IDELXU	ZXSSQ242
	WK(J) = ZERO	ZXSSQ243
25	CONTINUE	ZXSSQ244
	GO TO 165	ZXSSQ245
C		ZXSSQ246
	MAIN LOOP	ZXSSQ247
30	SSQOLD = SSQ	ZXSSQ248
C		ZXSSQ249
	CALCULATE JACOBIAN	ZXSSQ250
	IF (INFER.GT.0.OR.IJAC.GE.N.OR.IOPT.EQ.0.OR.ICOUNT.GT.0) GO TO 55	ZXSSQ251
C		ZXSSQ252
	RANK ONE UPDATE TO JACOBIAN	ZXSSQ253
	IJAC = IJAC+1	ZXSSQ254
	DSQ = ZERO	ZXSSQ255
	DO 35 J=IDELXL, IDELXU	ZXSSQ256
	DSQ = DSQ + WK(J) * WK(J)	ZXSSQ257
35	CONTINUE	ZXSSQ258
	IF (DSQ.LE.ZERO) GO TO 55	ZXSSQ259
	DO 50 I=1,M	ZXSSQ260
	G = FX(I) - WK(IFML1 + I)	ZXSSQ261
	K = I	ZXSSQ262
	DO 40 J=IDELXL, IDELXU	ZXSSQ263
	G = G + XJAC(K) * WK(J)	ZXSSQ264
	K = K+IXJAC	ZXSSQ265
40	CONTINUE	ZXSSQ266
	G = G/DSQ	ZXSSQ267
	K = I	ZXSSQ268
	DO 45 J=IDELXL, IDELXU	ZXSSQ269
	XJAC(K) = XJAC(K) - G * WK(J)	ZXSSQ270
	K = K+IXJAC	ZXSSQ271
45	CONTINUE	ZXSSQ272
50	CONTINUE	ZXSSQ273
	GO TO 80	ZXSSQ274
C		ZXSSQ275
	JACOBIAN BY INCREMENTING X	
55	IJAC = 0	
	K = -IMJC	
	DO 75 J=1,N	

	K = K+IMJC	ZXSSQ276
	XDABS = ABS(X(J))	ZXSSQ277
	HH = REL*(AMAX1(XDABS,AX))	ZXSSQ278
	XHOLD = X(J)	ZXSSQ279
	X(J) = X(J)+HH	ZXSSQ280
	CALL F(X,M,N,WK(IFPL))	ZXSSQ281
	IEVAL = IEVAL +1	ZXSSQ282
	X(J) = XHOLD	ZXSSQ283
	IF (ISW.EQ.1) GO TO 65	ZXSSQ284
C		
	CENTRAL DIFFERENCES	ZXSSQ285
	X(J) = XHOLD-HH	ZXSSQ286
	CALL F(X,M,N,WK(IFML))	ZXSSQ287
	IEVAL = IEVAL + 1	ZXSSQ288
	X(J) = XHOLD	ZXSSQ289
	RHH = HALF/HH	ZXSSQ290
	DO 60 I=IFPL,IFPU	ZXSSQ291
	K = K+1	ZXSSQ292
	XJAC(K) = (WK(I) - WK(I + M)) * RHH	ZXSSQ293
60	CONTINUE	ZXSSQ294
	GO TO 75	ZXSSQ295
C		
	FORWARD DIFFERENCES	ZXSSQ296
65	RHH = ONE/HH	ZXSSQ297
	DO 70 I=1,M	ZXSSQ298
	K = K+1	ZXSSQ299
	XJAC(K) = (WK(IFPL1 + I) - FX(I)) * RHH	ZXSSQ300
70	CONTINUE	ZXSSQ301
75	CONTINUE	ZXSSQ302
C		
	CALCULATE GRADIENT	ZXSSQ303
80	ERL2X = ERL2	ZXSSQ304
	ERL2 = ZERO	ZXSSQ305
	K = -IMJC	ZXSSQ306
	DO 90 J=IGRADL,IGRADU	ZXSSQ307
	K = K+IMJC	ZXSSQ308
	SUM = ZERO	ZXSSQ309
	DO 85 I=1,M	ZXSSQ310
	K = K+1	ZXSSQ311
	SUM = SUM+XJAC(K)*FX(I)	ZXSSQ312
85	CONTINUE	ZXSSQ313
	WK(J) = SUM	ZXSSQ314
	ERL2 = ERL2+SUM*SUM	ZXSSQ315
90	CONTINUE	ZXSSQ316
	ERL2 = SQRT(ERL2)	ZXSSQ317
C		
	CONVERGENCE TEST FOR NORM OF GRADIENT	ZXSSQ318
	IF (IJAC.GT.0) GO TO 95	ZXSSQ319
	IF (ERL2.LE.DELTA2) INFER = INFER+4	ZXSSQ320
	IF (ERL2.LE.CON2) ISW = 2	ZXSSQ321
C		
	CALCULATE THE LOWER SUPER TRIANGE OF	ZXSSQ322
C	JACOBIAN (TRANPOSED) * JACOBIAN	ZXSSQ323
95	L = 0	ZXSSQ324
	IS = -IXJAC	ZXSSQ325
	DO 110 I=1,N	ZXSSQ326
	IS = IS+IXJAC	ZXSSQ327
	JS = -IXJAC	ZXSSQ328
	DO 105 J=1,I	ZXSSQ329

JS = JS+IXJAC	ZXSSQ330
L = L+1	ZXSSQ331
SUM = ZERO	ZXSSQ332
DO 100 K=1,M	ZXSSQ333
LI = IS+K	ZXSSQ334
LJ = JS+K	ZXSSQ335
SUM = SUM+XJAC(LI)*XJAC(LJ)	ZXSSQ336
100 CONTINUE	ZXSSQ337
XJTJ(L) = SUM	ZXSSQ338
105 CONTINUE	ZXSSQ339
110 CONTINUE	ZXSSQ340
C CONVERGENCE CHECKS	ZXSSQ341
IF (INFER.GT.0) GO TO 315	ZXSSQ342
IF(IEVAL .GE. MAXFN) GO TO 295	ZXSSQ343
C COMPUTE SCALING VECTOR	ZXSSQ344
IF (IOPT.EQ.0) GO TO 120	ZXSSQ345
K = 0	ZXSSQ346
DO 115 J=1,N	ZXSSQ347
K = K+J	ZXSSQ348
WK(ISCAL1 + J) = XJTJ(K)	ZXSSQ349
115 CONTINUE	ZXSSQ350
GO TO 135	ZXSSQ351
C COMPUTE SCALING VECTOR AND NORM	ZXSSQ352
120 DNORM = ZERO	ZXSSQ353
K = 0	ZXSSQ354
DO 125 J=1,N	ZXSSQ355
K = K+J	ZXSSQ356
WK(ISCAL1 + J) = SQRT(XJTJ(K))	ZXSSQ357
DNORM = DNORM+XJTJ(K)*XJTJ(K)	ZXSSQ358
125 CONTINUE	ZXSSQ359
DNORM = ONE/SQRT(DNORM)	ZXSSQ360
C NORMALIZE SCALING VECTOR	ZXSSQ361
DO 130 J=ISCALL,ISCALU	ZXSSQ362
WK(J) = WK(J) * DNORM * ERL2	ZXSSQ363
130 CONTINUE	ZXSSQ364
C ADD L-M FACTOR TO DIAGONAL	ZXSSQ365
135 ICOUNT = 0	ZXSSQ366
140 K = 0	ZXSSQ367
DO 150 I=1,N	ZXSSQ368
DO 145 J=1,I	ZXSSQ369
K = K+1	ZXSSQ370
WK(K) = XJTJ(K)	ZXSSQ371
145 CONTINUE	ZXSSQ372
147 WK(K) = WK(K) + WK(ISCAL1 + I) * AL	ZXSSQ373
148 WK(IDELX1 + I) = WK(IGRAD1 + I)	ZXSSQ374
150 CONTINUE	ZXSSQ375
C CHOLESKY DECOMPOSITION	ZXSSQ376
155 CALL QXZ032 (WK,1,N,WK(IDELXL),N,0,G,XHOLD,IERR)	QXZNA276
IF(IERR.EQ.0) GO TO 160	ZXSSQ378
IERR = 0	ZXSSQ379
IF (IJAC.GT.0) GO TO 55	ZXSSQ380
IF (IBAD.LE.0) GO TO 240	ZXSSQ381
IF (IBAD.GE.2) GO TO 310	ZXSSQ382
GO TO 190	ZXSSQ383

160	IF (IBAD.NE.-99) IBAD = 0	ZXSSQ384
C	CALCULATE SUM OF SQUARES	ZXSSQ385
165	DO 170 J=1,N	ZXSSQ386
	WK(IXNEW1 + J) = X(J) - WK(IDELX1 + J)	ZXSSQ387
170	CONTINUE	ZXSSQ388
	CALL F(WK(IXNEWL),M,N,WK(IFPL))	ZXSSQ389
	IEVAL = IEVAL + 1	ZXSSQ390
	SSQ = ZERO	ZXSSQ391
	DO 175 I=IFPL,IFPU	ZXSSQ392
	SSQ = SSQ + WK(I) * WK(I)	ZXSSQ393
175	CONTINUE	ZXSSQ394
177	IF (ITER.GE.0) GO TO 185	ZXSSQ395
C	SSQ FOR INITIAL ESTIMATES OF X	ZXSSQ396
	ITER = 0	ZXSSQ397
	SSQOLD = SSQ	ZXSSQ398
	DO 180 I=1,M	ZXSSQ399
	FX(I) = WK(IFPL1 + I)	ZXSSQ400
180	CONTINUE	ZXSSQ401
	GO TO 55	ZXSSQ402
185	IF (IOPT.EQ.0) GO TO 215	ZXSSQ403
C	CHECK DESCENT PROPERTY	ZXSSQ404
	IF (SSQ.LE.SSQOLD) GO TO 205	ZXSSQ405
C	INCREASE PARAMETER AND TRY AGAIN	ZXSSQ406
190	ICOUNT = ICOUNT+1	ZXSSQ407
	AL = AL*FOSQ	ZXSSQ408
	IF (IJAC.EQ.0) GO TO 195	ZXSSQ409
	IF (ICOUNT.GE.4.OR.AL.GT.UP) GO TO 200	ZXSSQ410
195	IF (AL.LE.UP) GO TO 140	ZXSSQ411
	IF (IBAD.EQ.1) GO TO 310	ZXSSQ412
	GO TO 300	ZXSSQ413
200	AL = AL/FOSQS4	ZXSSQ414
	GO TO 55	ZXSSQ415
C	ADJUST MARQUARDT PARAMETER	ZXSSQ416
205	IF (ICOUNT.EQ.0) AL = AL/FO	ZXSSQ417
	IF (ERL2X.LE.ZERO) GO TO 210	ZXSSQ418
	G = ERL2/ERL2X	ZXSSQ419
	IF (ERL2.LT.ERL2X) AL = AL*AMAX1(ONESFO,G)	ZXSSQ420
	IF (ERL2.GT.ERL2X) AL = AL*AMIN1(FO,G)	ZXSSQ421
210	AL = AMAX1(AL,PREC)	ZXSSQ422
C	ONE ITERATION CYCLE COMPLETED	ZXSSQ423
215	ITER = ITER+1	ZXSSQ424
	DO 220 J=1,N	ZXSSQ425
	X(J) = WK(IXNEW1 + J)	ZXSSQ426
220	CONTINUE	ZXSSQ427
	DO 225 I=1,M	ZXSSQ428
	WK(IFML1 + I) = FX(I)	ZXSSQ429
	FX(I) = WK(IFPL1 + I)	ZXSSQ430
225	CONTINUE	ZXSSQ431
C	RELATIVE CONVERGENCE TEST FOR X	ZXSSQ432
	IF (ICOUNT.GT.0.OR.IJAC.GT.0) GO TO 30	ZXSSQ433
	DO 230 J=1,N	ZXSSQ434
	XDIF = ABS(WK(IDELX1 + J)) / AMAX1(ABS(X(J)),AX)	ZXSSQ435
	IF (XDIF.GT.RELCON) GO TO 235	ZXSSQ436
230	CONTINUE	ZXSSQ437

	INFER = INFER + 2	ZXSSQ438
C	RELATIVE CONVERGENCE TEST FOR SSQ	ZXSSQ439
235	SQDIF = ABS(SSQ-SSQOLD)/AMAX1(SSQOLD,AX)	ZXSSQ440
	IF (SQDIF .LE. EPS) INFER = INFER+1	ZXSSQ441
	IF(IBAD .EQ. -99) GO TO 30	ZXSSQ442
	IF(INFER .NE. 0 .AND. SSQ .GT. (10.0 * EPS)) GO TO 310	ZXSSQ443
	GO TO 30	ZXSSQ444
C	SINGULAR DECOMPOSITION	ZXSSQ445
240	IF (IBAD) 255,245,265	ZXSSQ446
C	CHECK TO SEE IF CURRENT	ZXSSQ447
C	ITERATE HAS CYCLED BACK TO	ZXSSQ448
C	THE LAST SINGULAR POINT	ZXSSQ449
245	DO 250 J=1,N	ZXSSQ450
	XHOLD = WK(IXBAD1 + J)	ZXSSQ451
	IF (ABS(X(J)-XHOLD).GT.RELCON*AMAX1(AX,ABS(XHOLD))) GO TO 255	ZXSSQ452
250	CONTINUE	ZXSSQ453
	GO TO 310	ZXSSQ454
C	UPDATE THE BAD X VALUES	ZXSSQ455
255	DO 260 J=1,N	ZXSSQ456
	WK(IXBAD1 + J) = X(J)	ZXSSQ457
260	CONTINUE	ZXSSQ458
	IBAD = 1	ZXSSQ459
C	INCREASE DIAGONAL OF HESSIAN	ZXSSQ460
265	IF (IOPT.NE.0) GO TO 280	ZXSSQ461
	K = 0	ZXSSQ462
	DO 275 I=1,N	ZXSSQ463
	DO 270 J=1,I	ZXSSQ464
	K = K+1	ZXSSQ465
	WK(K) = XJTJ(K)	ZXSSQ466
270	CONTINUE	ZXSSQ467
	WK(K) = ONEP5 * (XJTJ(K) + AL * ERL2 * WK(ISCAL1 + I)) + REL	ZXSSQ468
275	CONTINUE	ZXSSQ469
	IBAD = 2	ZXSSQ470
	GO TO 155	ZXSSQ471
C	REPLACE ZEROES ON HESSIAN DIAGONAL	ZXSSQ472
280	IZERO = 0	ZXSSQ473
	DO 285 J=ISCALL,ISCALU	ZXSSQ474
	IF(WK(J) . GT . ZERO) GO TO 285	ZXSSQ475
	IZERO = IZERO+1	ZXSSQ476
	WK(J) = ONE	ZXSSQ477
285	CONTINUE	ZXSSQ478
	IF (IZERO.LT.N) GO TO 140	ZXSSQ479
C	TERMINAL ERROR	ZXSSQ480
290	IERR = IERR + 1	ZXSSQ481
295	IERR = IERR + 1	ZXSSQ482
300	IERR = IERR + 1	ZXSSQ483
305	IERR = IERR + 1	ZXSSQ484
310	CONTINUE	ZXSSQ485
	IERR = IERR + 1	ZXSSQ486
	IF (IERR . EQ . 2) GO TO 9005	ZXSSQ487
C	OUTPUT ERL2,IEVAL,NSIG,AL, AND ITER	ZXSSQ488
315	G = SIG	ZXSSQ489
	DO 320 J=1,N	ZXSSQ490
	XHOLD = ABS(WK(IDELX1 + J))	ZXSSQ491

IF (XHOLD.LE.ZERO) GO TO 320	ZXSSQ492
G = AMIN1(G,-ALOG10(XHOLD)+ALOG10(AMAX1(AX,ABS(X(J))))))	ZXSSQ493
320 CONTINUE	ZXSSQ494
IF(N.GT.2) GO TO 330	ZXSSQ495
DO 325 J = 1,N	ZXSSQ496
325 WK(J+5) = WK(J+IGRAD1)	ZXSSQ497
330 WK(1) = ERL2+ERL2	ZXSSQ498
WK(2) = IEVAL	ZXSSQ499
SSQ = SSQOLD	ZXSSQ500
WK(3) = G	ZXSSQ501
WK(4) = AL	ZXSSQ502
WK(5) = ITER	ZXSSQ503
9005 RETURN	ZXSSQ504
END	ZXSSQ505
SUBROUTINE QXZ032 (A,M,N,B,IB,IDGT,D1,D2,IER)	QXZNA279
C	LEQT1P 3
C LANGUAGE - FORTRAN	LEQT1P39
C	LEQT1P42
DIMENSION A(1),B(IB,1)	LEQT1P43
C INITIALIZE IER	LEQT1P44
IER = 0	LEQT1P45
C DECOMPOSE A	LEQT1P46
CALL QXZ033 (A,A,N,D1,D2,IER)	QXZNA282
IF (IER.NE.0) GO TO 9005	LEQT1P48
C PERFORM ELIMINATION	LEQT1P49
DO 5 I = 1,M	LEQT1P50
CALL QXZ034 (A,B(1,I),N,B(1,I))	QXZNA283
5 CONTINUE	LEQT1P52
9005 RETURN	LEQT1P53
END	LEQT1P54
SUBROUTINE QXZ033 (A,UL,N,D1,D2,IER)	QXZNA286
C	LUDECP 3
C PRECISION - SINGLE	LUDECP25
DIMENSION A(1),UL(1)	LUDECP31
DATA ZERO,ONE,FOUR,SIXTN,SIXTH/0.0,1.,4.,16.,.0625/	LUDECP32
D1=ONE	LUDECP33
D2=ZERO	LUDECP34
RN = ONE/(N*SIXTN)	LUDECP35
IP = 1	LUDECP36
IER=0	LUDECP37
DO 45 I = 1,N	LUDECP38
IQ = IP	LUDECP39
IR = 1	LUDECP40
DO 40 J = 1,I	LUDECP41
X = A(IP)	LUDECP42
IF (J .EQ. 1) GO TO 10	LUDECP43
DO 5 K=IQ,IP1	LUDECP44
X = X-UL(K)*UL(IR)	LUDECP45
IR = IR+1	LUDECP46
5 CONTINUE	LUDECP47
10 IF (I.NE.J) GO TO 30	LUDECP48
D1 = D1*X	LUDECP49
IF (A(IP)+X*RN .LE. A(IP)) GO TO 50	LUDECP50
15 IF (ABS(D1) .LE. ONE) GO TO 20	LUDECP51

	D1 = D1 * SIXTH	LUDECP52
	D2 = D2 + FOUR	LUDECP53
	GO TO 15	LUDECP54
20	IF (ABS(D1) .GE. SIXTH) GO TO 25	LUDECP55
	D1 = D1 * SIXTN	LUDECP56
	D2 = D2 - FOUR	LUDECP57
	GO TO 20	LUDECP58
25	UL(IP) = ONE/SQRT(X)	LUDECP59
	GO TO 35	LUDECP60
30	UL(IP) = X * UL(IR)	LUDECP61
35	IP1 = IP	LUDECP62
	IP = IP+1	LUDECP63
	IR = IR+1	LUDECP64
40	CONTINUE	LUDECP65
45	CONTINUE	LUDECP66
	GO TO 9005	LUDECP67
50	IER = 129	LUDECP68
9000	CONTINUE	LUDECP69
9005	RETURN	LUDECP70
	END	LUDECP71
	SUBROUTINE QXZ034 (A,B,N,X)	QXZNA290
C		LUELMP 3
C		LUELMP25
	DIMENSION A(1),B(1),X(1)	LUELMP26
	DATA ZERO/0./	LUELMP27
C	SOLUTION OF LY = B	LUELMP28
	IP=1	LUELMP29
	IW = 0	LUELMP30
	DO 15 I=1,N	LUELMP31
	T=B(I)	LUELMP32
	IM1 = I-1	LUELMP33
	IF (IW .EQ. 0) GO TO 9	LUELMP34
	IP=IP+IW-1	LUELMP35
	DO 5 K=IW,IM1	LUELMP36
	T = T-A(IP)*X(K)	LUELMP37
	IP=IP+1	LUELMP38
5	CONTINUE	LUELMP39
	GO TO 10	LUELMP40
9	IF (T .NE. ZERO) IW = I	LUELMP41
	IP = IP+IM1	LUELMP42
10	X(I)=T*A(IP)	LUELMP43
	IP=IP+1	LUELMP44
15	CONTINUE	LUELMP45
C	SOLUTION OF UX = Y	LUELMP46
	N1 = N+1	LUELMP47
	DO 30 I = 1,N	LUELMP48
	II = N1-I	LUELMP49
	IP=IP-1	LUELMP50
	IS=IP	LUELMP51
	IQ=II+1	LUELMP52
	T=X(II)	LUELMP53
	IF (N.LT.IQ) GO TO 25	LUELMP54
	KK = N	LUELMP55
	DO 20 K=IQ,N	LUELMP56

	T = T-A(IS)*X(KK)	LUELMP57
	KK = KK-1	LUELMP58
	IS = IS-KK	LUELMP59
20	CONTINUE	LUELMP60
25	X(II)=T*A(IS)	LUELMP61
30	CONTINUE	LUELMP62
	RETURN	LUELMP63
	END	LUELMP64

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16 Abstract <p>Wide angle x-ray scattering (WAXS) data from poly(etheretherketone) (PEEK) has been resolved into a crystalline contribution represented as 4 reflections and an amorphous contribution represented as a broad, smoothly varying curve, both contributions occurring in the 2θ range: 15-31 degrees. In this resolution the crystalline scatter is described as a linear combination of Cauchy and Gaussian functions while that of the amorphous halo is expressed as a cubic polynomial. Statistical analysis of the measured scattered intensity from an amorphous specimen with that calculated from the cubic polynomial, as a function of the combination parameter (fraction of Cauchy and Gaussian functions), suggests that the crystalline fraction of the polymer specimen studied is about 0.39. A listing of the FORTRAN IV program used in the resolution is provided in the Appendix.</p>					
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